Abstracts

Discontinuities in Fin-Line on Semiconductor Substrate (1986 [MWSYM])

K. Uhde. "Discontinuities in Fin-Line on Semiconductor Substrate (1986 [MWSYM])." 1986 MTT-S International Microwave Symposium Digest 86.1 (1986 [MWSYM]): 703-706.

Discontinuities in both slot width and substrate complex dielectric constant are investigated theoretically. The fin-line slot pattern is defined on a double-layer substrate with finite conductivity. Numerical results are presented showing that a step in the permittivity can almost be compensated for by a step in the slotwidth.

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